

Search Notes

Application/Control No.

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Examiner

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Reexamination

LAI ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
708	700, 708	9/20/2006	MAI

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout)	9/20/2006	MAI
Data Bases Search (see search history printout)	9/22/2006	MAI